

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10574286	OIKAWA ET AL.
	Examiner	Art Unit
	CEDRIC CHAN	1797

SEARCHED

Class	Subclass	Date	Examiner
422	50,68.1,82.05,99,104	2/13/2010	CC
436	73	2/13/2010	CC

SEARCH NOTES

Search Notes	Date	Examiner
inventor name search (PALM)	2/5/2010	CC
inventor name search (EAST)	2/13/2010	CC
searched US/Foreign databases -- EAST/USPat,OCR,PGPub,EPO,JPO,Derwent	2/13/2010	CC

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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